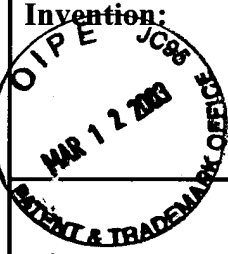


CERTIFICATE OF MAILING BY FIRST CLASS MAIL (37 CFR 1.8) Applicant(s): Masahiro Ishida, et al.			Docket No. 02008.071001; AD-0243PCTUS
Serial No. 09/980,891	Filing Date December 3, 2001	Examiner T. Nguyen	Group Art Unit 2829

Invention:



METHOD AND APPARATUS FOR DEFECT ANALYSIS OF SEMICONDUCTOR INTEGRATED CIRCUIT

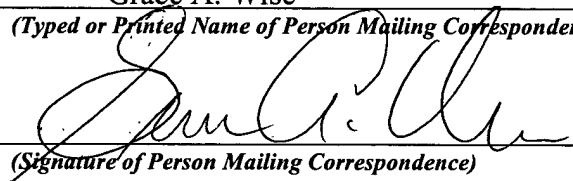
I hereby certify that this Preliminary Amendment along with required papers
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is being deposited with the United States Postal Service as first class mail in an envelope addressed to:

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